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APPENDIX 2: Data of EMI test

Automatically deactivate

UL Japan, Inc.

Head Office EMC Lab. No.3 Semi Anechoic Chamber

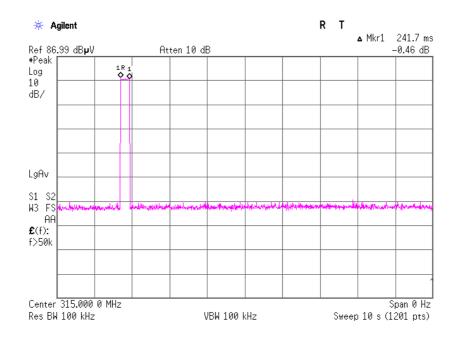
COMPANY : Mitsubishi Electric Corporation Himeji Works REGULATION : FCC15.231(a)(1)

EQUIPMENT : SMART KEYLESS SYSTEM (TRANSMITTER) TEST DISTANCE : -

MODEL : SKE11A-03 DATE : 05/16/2008 S/N : 20080424-02 TEMPERATURE : 25 deg.C. **POWER** : DC 3.0V (CR2025) HUMIDITY : 44% Mode : Normal use mode **ENGINEER** : Akio Hayashi

Axis : -

Time of	Limit	Result
Transmitting		
[sec]	[sec]	
0.24	5.00	Pass



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Radiated Emission (Electric Field Strength of Fundamental and Spurious Emission)

UL Japan, Inc.

Head Office EMC Lab. No.3 Semi Anechoic Chamber

COMPANY : Mitsubishi Electric Coporation Himeji Works REPORT NO : 281E0193-HO-01

EQUIPMENT : SMART KEYLESS SYSTEM (TRANSMITTER) REGULATION : FCC Part 15 Subpart C 15.231(b) / 15.205 / 15.209

MODEL SKE11A-03 TEST DISTANCE : 3 m S/N : 20080424-01 DATE : 05/09/2008 POWER : DC 3.0V (CR2025) TEMPERATURE : 22 deg.C. : Transmitting mode HUMIDITY : 50% Mode EUT Axis : Hor .: X-axis , Ver .: Z-axis ENGINEER · Takumi Shimada

PK DETEC T

No.	FREQ	T/R RE	ADING	ANT	AMP	LOSS	Duty	RESULT		RESULT		Limit	MAF	RGIN
		HOR	VER	Factor	GAIN		Factor	HOR VER			HOR	VER		
	[MHz]	[dB	uV]	[dB/m]	[dB]	[dB]	[dB]	[dBuV/m]		[dBuV/m]	[dB]	[dB]		
1	315.00	82.2	78.6	15.0	32.0	10.0	-	75.2	71.6	75.6	0.4	4.0		
2	630.00	25.7	31.7	19.4	32.0	11.9	-	25.0	31.0	55.6	30.6	24.6		
3	945.00	36.2	32.4	22.2	30.8	13.4	-	41.0	37.2	55.6	14 6	18.4		

 PK DETEC T
 (RBW: 1MHz, VBW: 1MHz)
 (Inside Restricted bands)

 No.
 FREQ
 S/A READING
 ANT
 AMP
 LOSS
 Duty
 RESULT
 Limit
 MARGIN

 HOR
 VER
 Factor
 GAIN
 Factor
 HOR
 VER
 HOR
 HOR

110.	1102	5,11 102				2000	Daty	ICLU	TELDO LI			
		HOR	VER	Factor	GAIN		Factor	HOR	VER		HOR	VER
	[MHz]	[dB	BuV]	[dB/m]	[dB]	[dB]	[dB]	[dBu	V/m]	[dBuV/m]	[dB]	[dB]
5	1575.00	53.9	57.0	25.7	33.8	2.3	-	48.1	51.2	53.9	5.8	2.7
7	2205.00	53.1	52.5	26.3	32.9	2.6	-	49.1	48.5	53.9	4.8	5.4
9	2835.00	42.8	44.6	27.6	32.6	2.9	-	40.7	42.5	53.9	13.2	11.4

Result = Reading (RBW: 1MHz, VBW: 1MHz) PK DETECT (Outside Restricted bands) FREQ S/A READING ANT AMP LOSS RESULT Limit MARGIN HOR VER Factor GAIN HOR VER HOR VER ı Factor [MHz [dB/m [dB] [dB] [dBuV/m 1890.00 46.8 48.2 25.8 33.2 41.8 43.2 55.6 13.8 12.4 2520.00 51.2 50.1 27 0 32.8 48 1 47.0 55.6 7.5 8.6 3150.00 28.2 32.4 55.6 52.3

REMARKS ANTENNA TYPE:30-300MHz Biconical / 300-1000MHz Logperiodic / 1-3.2GHz Horn

CALCULATION RESULT=Reading + ANT Factor - Amp Gain + LOSS (Cable+ ATTEN.)

- * The tests below and above 1GHz were performed with PK DETECT.
- * Applying the limit of AV to the PK data, there were some margin and it was adopted.
- * The result is rounded off to the second decimal place, so some differences might be observed.
- *The limit was converted from V to dBuV, and it is rounded off to the second decimal place.
- *Except for the above table : All other spurious emissions were less than 20dB for the limit.

The carrier level (or, noise levels) was (or were) measured at each position of all three axes X, Y and Z, and the position that has the maximum noise was determined. With the position, the noise levels of all the frequencies was measured.

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-20dB Bandwidth

UL Japan, Inc.

Head Office EMC Lab. No.3 Semi Anechoic Chamber

COMPANY : Mitsubishi Electric Corporation Himeji Works REGULATION : FCC15.231(c)

EQUIPMENT : SMART KEYLESS SYSTEM (TRANSMITTER) TEST DISTANCE

MODEL : SKE11A-03 S/N : 20080424-01 POWER : DC 3.0V (CR2025) Mode : Transmitting mode

Axis : X-axis

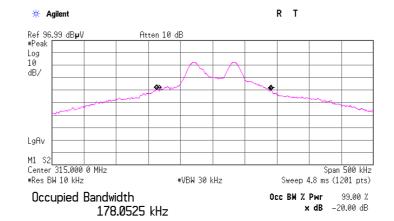
DATE : 05/16/2008

: 25 deg.C. TEMPERATURE HUMIDITY : 44%

ENGINEER : Akio Hayashi

Bandwidth Limit: Fundamental Frequency 315 MHz X 0.25% = 787.50 kHz

-20dB Bandwidth	Bandwidth Limit	Result
[kHz]	[kHz]	
151.46	787.50	Pass



Transmit Freq Error x dB Bandwidth 1.382 kHz 151.463 kHz

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99% Occupied Bandwidth

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Head Office EMC Lab. No.3 Semi Anechoic Chamber

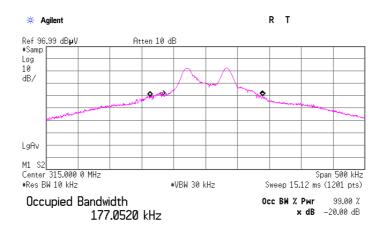
COMPANY : Mitsubishi Electric Corporation Himeji Works REGULATION : RSS-210 A1.1.3 **EQUIPMENT** : SMART KEYLESS SYSTEM (TRANSMITTER) DATE : 05/16/2008 : 25 deg.C. MODEL : SKE11A-03 TEMPERATURE S/N : 20080424-01 HUMIDITY : 44% POWER : DC 3.0V (CR2025) **ENGINEER** : Akio Hayashi

Mode : Transmitting mode

Axis : X-axis

Bandwidth Limit: Fundamental Frequency 315 MHz X 0.25% = 787.50 kHz

99% Occupied Bandwidth	Bandwidth Limit	Result
[kHz]	[kHz]	
177.05	787.50	Pass



Transmit Freq Error 1.585 kHz x dB Bandwidth 132.368 kHz*

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: August 21, 2008 FCC ID : WAZX1T768SKE11A03

Duty Cycle(Fundamental)

UL Japan, Inc. Head Office EMC Lab. No.3 Semi Anechoic Chamber

COMPANY EQUIPMENT MODEL

: Mitsubishi Electric Corporation Himeji Works : SMART KEYLESS SYSTEM (TRANSMITTER) : SKE11A-03

20080424-02 : DC 3.0V (CR2025) : Normal use mode

REGULATION : FCC 15.231(b) / 15.35(c)

TEST DISTANCE

05/16/2008 DATE 25 deg.C TEMPERATURE HUMIDITY ENGINEER : Akio Hayashi

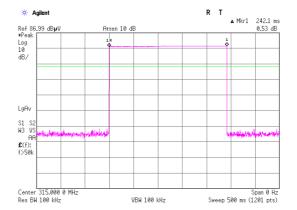
ON time	Cycle	Duty	Duty		
[ms]	[ms]	(On time/Cycle)	[dB]		
100.00	100.00	1.00	0.0		

 $Duty = 20log_{10}(ON time/Cycle)$

S/N

POWER

Mode



UL Japan, Inc. **Head Office EMC Lab.**

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: 28IE0193-HO-01-A-R2 Test report No.

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FCC ID : WAZX1T768SKE11A03

Receiver Spurious Emission

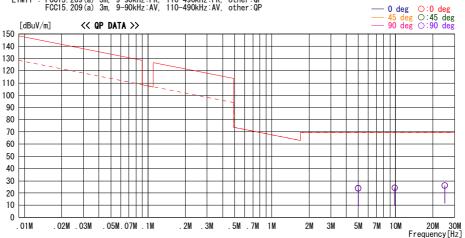
DATA OF RADIATED EMISSION TEST

Head Office EMC Lab. No.1 Semi Anechoic Chamber Date: 2008/05/19

281E0193-H0-01 DC 3V 23deg. C / 53% Takumi Shimada Company Kind of EUT Model No. Serial No. : Mitsubishi Electric Corporation : SMART KEYLESS SYSTEM (TRANSMITTER) : SKE11A-03 : 20080424-02 Report No. Power Temp. / Humi. Operator

Mode / Remarks : LF Receiving Mode

LIMIT : FCC15.209(a) 3m, 9-90kHz:PK, 110-490kHz:PK, other:QP FCC15.209(a) 3m, 9-90kHz:AV, 110-490kHz:AV, other:QP



	Freq.	Reading	DET	Ant. Fac	Loss	Gain	Result	Limit	Margin	Ant enna	Table
	[MHz]	[dBuV]		[dB/m]	[dB]	[dB]	[dBuV/m]	[dBuV/m]	[dB]		[deg]
Г	5.00000	41.3	QP	20.2	0. 7	38. 2	24.0	69. 5	45. 5	0deg	0
	5.00000	41.3	QP	20. 2	0. 7	38. 2	24.0		45. 5	45deg	0
	5.00000	41.4	QP	20. 2	0. 7	38. 2	24.1	69. 5	45. 4	90deg	0
	9.84375	41.2	QP	20.3	1. 0	38. 2	24.3	69. 5	45. 2	0deg	0
	9.84375	41.4	QP	20.3	1. 0		24.5		45. 0		0
	9.84375	41.2	QP	20.3	1. 0	38. 2	24.3		45. 2	90deg	0
	25.00000	41.7	QP	21.0	1. 7		26.2		43. 3	0deg	0
	25.00000	41.8	QP	21.0	1. 7	38. 2	26.3	69. 5	43. 2	45deg	0
	25.00000	41.8	QP	21.0	1. 7	38. 2	26.3	69. 5	43. 2	90deg	0

CHART : WITH FACTOR, ANT TYPE: LOOP, Except for the data below: adequate margin data below the limits. CALCULATION: READING + ANT FACTOR + LOSS(CABLE + ATTEN.-AMP.)

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^{*}The test result is rounded off to one or two decimal places, so some differences might be observed.

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Receiver Spurious Emission

DATA OF RADIATED EMISSION TEST
UL Japan, Inc. Head Office EMC Lab. No. 1 Semi Anechoic Chamber
Date: 2008/05/19

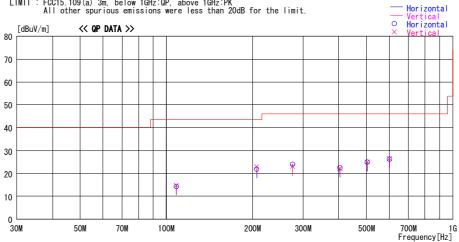
Mitsubishi Electric Corporation Himeji Works SMART KEYLESS SYSTEM (TRANSMITTER) SKEI1A-03 20080424-02 Company Kind of EUT Model No. Serial No.

Report No. Power Temp./Humi. Operator

: 281E0193-H0-01 : DC 3V : 23eg.C. / 53% : Takumi Shimada

Mode / Remarks : LF Receiving mode

LIMIT : FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:PK All other spurious emissions were less than 20dB for the limit.



Frequency	Reading	DET	Antenna Factor	Loss& Gain	Level	Angle	Height	Polar.	Limit	Margin
[MHz]	[dBuV]		[dB/m]	[dB]	[dBuV/m]	[Deg]	[cm]		[dBuV/m]	[dB]
108.281	23.0	QP	10.8	-19. 4	14. 4	0	300	Hori.	43. 5	29. 1
108.281	23. 4	QP	10.8	-19. 4	14. 8	0	100	Vert.	43. 5	28. 7
206.719	23. 1	QP	16. 7	-17. 8			300	Hori.	43. 5	
206.719	24.0	QP	16. 7	-17. 8			100	Vert.	43. 5	
275.625		QP	18. 6	-16. 9		0	300	Hori.	46. 0	
275.625		QP	18. 6	-16. 9			100	Vert.	46. 0	
403.594	22. 3	QP	16. 7	-16. 5			100	Hori.	46. 0	
403.594	22. 1	QP	16. 7	-16. 5			100	Vert.	46. 0	23. 8
502.031	23. 1	QP	18. 2	-16. 2		359	100	Hori.	46. 0	
502.031	23. 0	QP	18. 2	-16. 2		359	100	Vert.	46. 0	21. 0
600.469	22. 8	QP	19. 2	-15. 7			100	Hori.	46. 0	
600.469	22. 9	QP	19. 2	-15. 7	26. 4	359	100	Vert.	46. 0	19. 6

CHART: WITH FACTOR ANT TYPE: -30MHz LOOP, 30-300MHz BICONICAL, 300MHz-1000MHz LOGPERIODIC, 1000MHz- HORN CALCULATION: RESULT = READING + ANT FACTOR + LOSS (CABLE+ATTEN.) - GAIN (AMP)

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^{*}The test result is rounded off to one or two decimal places, so some differences might be observed.

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APPENDIX 3:Test Instruments

EMI test equipment

Emii test equ	pinent				
Control No. Instrument		Manufacturer	Model No	Test Item	Calibration Date * Interval(month)
MAEC-03	Anechoic Chamber	TDK	Semi Anechoic Chamber 3m	RE	2008/03/25 * 12
MOS-13	Thermo-Hygrometer	Custom	CTH-180	RE	2008/01/10 * 12
MJM-06	Measure	PROMART	SEN1955	RE	-
MSTW-14	EMI measurement program	TSJ	TEPTO-DV	RE	-
MSA-04	Spectrum Analyzer	Agilent	E4448A	RE	2007/06/20 * 12
MTR-02	Test Receiver	Rohde & Schwarz	ESCS30	RE	2008/02/20 * 12
MBA-03	Biconical Antenna	Schwarzbeck	BBA9106	RE	2008/01/12 * 12
MLA-03	Logperiodic Antenna	Schwarzbeck	USLP9143	RE	2008/01/12 * 12
MCC-51	Coaxial cable	UL Japan	-	RE	2007/07/26 * 12
MAT-30	Attenuator(6dB)	TME	UFA-01	RE	2008/03/10 * 12
MPA-13	Pre Amplifier	SONOMA INSTRUMENT	310	RE	2008/03/06 * 12
MCC-56	Microwave Cable 1G- 26.5GHz	Suhner	SUCOFLEX104	RE	2008/03/12 * 12
MPA-11	MicroWave System Amplifier	Agilent	83017A	RE	2008/03/13 * 12
MHA-20	Horn Antenna 1- 18GHz	Schwarzbeck	BBHA9120D	RE	2008/04/23 * 12
MRENT-67	Spectrum Analyzer	Agilent	E4448A	RE	2008/04/02 * 12
MAEC-01	Anechoic Chamber	TDK	Semi Anechoic Chamber 10m	RE	2007/11/23 * 12
MLPA-01	Loop Antenna	Rohde & Schwarz	HFH2-Z2	RE	2007/11/06 * 12
MCC-30	Coaxial cable	UL Japan	-	RE	2007/06/04 * 12
MCC-03	Coaxial Cable	Fujikura/Suhner/Agil ent/TSJ	-	RE	2007/12/27 * 12
MPA-19	Pre Amplifier	MITEQ	MLA-10K01-B01-35	RE	2008/02/13 * 12
MTR-01	Test Receiver	Rohde & Schwarz	ESI40	RE	2007/10/19 * 12
MOS-01	Digital Humidity Indicator	N.T	NT-1800	RE	2007/11/12 * 12
MJM-01	Measure	KDS	ES19-55	RE	-
MBA-01	Biconical Antenna	Schwarzbeck	BBA9106	RE	2007/10/21 * 12
MLA-09	Logperiodic Antenna	Schwarzbeck	USLP9143B	RE	2008/01/12 * 12
MAT-06	Attenuator(6dB)	Weinschel Corp	2	RE	2007/11/14 * 12
MCC-01	Coaxial Cable 0.1- 3000MHz	Suhner/storm/Agilent /TSJ	-	RE	2008/02/29 * 12
MPA-04	Pre Amplifier	Agilent	8447D	RE	2007/07/11 * 12
					•

The expiration date of the calibration is the end of the expired month.

All equipment is calibrated with traceable calibrations. Each calibration is traceable to the national or international standards. As for some calibrations performed after the tested dates, those test equipment have been controlled by means of an unbroken chains of calibrations.

Test Item:

RE: Radiated emission, 99% Occupied Bandwidth, -20dB bandwidth, Automatically deactivate and Duty cycle tests

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